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UDK 662.762.3:551.463.5 Raman and IR Spectra of Pure and Doped Forsterite Single Crystals

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Abstract:

Forsterite single crystals were grown by the Czochralski technique in air. The lattice parameters were determined by X-ray power diffraction. The IR and Raman spectra of pure and doped $(V^{3+}, V^{5+}, and Ni^{4+}) Mg_2SiO_4$ single crystals were measured at room temperature. We studied the phonon properties and discussed the influence of dopants. **Keywords**: Forsterite; X-ray diffraction; IR spectra; Raman spectra; Optical properties.

Introduction

The most abundant mineral in the lower part of the transition zone of the earth, α -Mg₂SiO₄ (forsterite) has extremely low electrical conductivity, low dielectric-constant ε_r , and low dielectric-losses. These properties make forsterite an ideal substrate and buffer layer material for microwave devices [1]. When it is doped by chromium, forsterite is used as an active medium for solid state lasers [2]. This important discovery has prompted the investigation of its spectroscopic properties. Aside from exploring optical properties in the visible range, special attention has been paid to vibrational spectra, particularly to the local A₁ mode which plays an important role in the mechanism for non-radiative deexcitation in the ³T₁ crystal field (CF) state [3]. This mode is also the only local one involved in the vibrational progression observed in the low temperature optical spectra [4]. The aim of this work is to study the phonon properties of pure and doped Mg₂SiO₄ single crystals (dopants V₂O₃, V₂O₅, NiO₂) in order to provide more understanding of the vibrational structure of this well-known crystal.

Experimental

Forsterite single crystals were grown from a stoichiometric melt by the Czochralski method from indium crucibles using RF heating. All crystals were grown on seeds oriented along the a-axis (P_{bnm} notation). The pulling rate was 3 mm/h and the rotation rate 12 rpm.

The dopant concentration was 1 wt. %, as usually taken in the case of forsterite. The dopant concentrations were checked by microprobe analysis.

The chemical composition was determined by XRD on powders. A Phillips 1710 diffractometer with the radiation $\lambda CuK\alpha_1 = 0.15405$ nm source and original APD software was used. The samples were pressed into standard aluminium frames and the measured range

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for 2θ was from 10° to 100° . The spectra were obtained at the step of 0.02° . For production identification, the MPDS program and JCPDS (ASTM) card files were used.

The infrared spectra were recorded using a Bomem DA8 Fourier-transform spectrometer. A wide-range hypersplitter was used for the far infrared region (from 20-700 cm⁻¹) and a standard KBr (400-5000 cm⁻¹) one for the mid infrared region. All the spectra were recorded at a near normal incidence at room temperature. The measurements were performed using a Janis STDA 100 cryostat, which enabled the precise exchange of the sample and the mirror at the same spot on the cold finger.

The Raman spectra were measured at room temperature using a T64000 Jobin-Yvon triple monochromator coupled with a liquid-N₂-cooled charge-coupled device detector. The Raman scattering measurements were performed in a backscattering configuration. The 514.5 nm line of an argon ion laser with output power of 50 mW was used. The laser spot size on the sample surface was obtained by a microscope setup with 10x objective magnification.

Results and Discussion

Forsterite, a member of the olivine family, has an orthorhombic lattice structure with the space group P_{bnm} (a = 4.76 Å, b = 10.22 Å, c = 5.99 Å). In the lattice, Mg²⁺ ions are in two crystallographic positions, 4a and 4c, which have inversion and mirror point symmetry, respectively. Si⁴⁺ ions are in the 4c position with mirror point symmetry. The Si⁴⁺ tetrahedron connects with two types of Mg²⁺ octahedrons.

Unit cells of pure and doped Mg_2SiO_4 were calculated by the least square method using 39 reflections. All the reflections correspond to Mg_2SiO_4 crystal with parameters of the orthorhombic unit cell: a = 0.4765 (6) nm, b = 1.023 and c = 0.5997 (7) nm [5]. Our calculated results for the lattice parameters of doped forsterite are a = 0.4752 (2) nm, b =1.0191 (1) nm, c = 0.5977 (1) nm for V_2O_3 dopant, a = 0.475037 (2)nm, b = 1.01896 (5) nm, c =0.59744 (1) nm for V_2O_5 dopant, and a = 0.4453 (2) nm, b = 1.0187 (1) nm, c = 0.5976 (1) nm for NiO₂ dopant, which are in good agreement with the published data. An X-ray diffractogram for powdered Mg_2SiO_4 is given in Fig. 1.



Fig. 1 X-ray pattern of a powdered V₂O₅ doped Mg₂SiO₄ single crystal.

Forsterite host Mg₂SiO₄ enables vanadium ions to be present in different oxidation states and structural localization. In the crystal structure of forsterite there are two types of Mg-octahedra which distort symmetries C_i (M₁) and C_s (M₂), as well as Si-tetrahedra that is distorted the C_s symmetry. The octahedra M₁ have a smaller size, than M₂. The ionic radii of the host and dopant ions are the following: 0.72 and 0.64 Å for octahedral Mg²⁺ and V³⁺, respectively, and 0.40, and 0.54 Å for the tetrahedral coordinated Si⁴⁺, and V⁵⁺, respectively [6], whereas Ni⁴⁺ substituted the tetrahedral coordinated Si⁴⁺ (ionic radius 0.69 Å).

The covalence effects have been partially taken into account by the potential bending of valent angle O-Si-O and by the assumption about polarizability of oxygen ions. In the case of heterovalent substitution it was supposed, that an excess charge is compensated by the formation of magnesium vacancies (in the sites M₁, as energetically most favorable).

Fig. 2 represents IR spectra of forsterite single crystals doped with V_2O_3 and V_2O_5 , respecttively.



Fig. 2 Reflectance spectra of Mg₂SiO₄ single crystals doped with V_2O_3 and V_2O_5 in the range 50-1300 cm⁻¹ at T=298 K.

It could be seen from Fig. 2 that differences induced from various dopants (V_2O_3 and V_2O_5) are between wave numbers 365 and 476 cm⁻¹. For dopant V_2O_3 impurity three modes appear at 380, 438 and 476 cm⁻¹, while for dopant V_2O_5 , the modes appear at 365, 402 and 459 cm⁻¹, and an additional one at 836 cm⁻¹. The last one belongs to O²⁻ vibations in the SiO₄ group, while the others can be assigned to cation bonds. The mode at 954 cm⁻¹ is split probably due to anharmonicity. Forsterite has partly covalent bonding and this must be taken into account.

The irreducible representation of the forsterite contains 81 vibrational modes [7]:

 $\Gamma = 11A_{g} + 11B_{1g} + 7B_{2g} + 7B_{3g} + 10A_{u} + 9B_{1u} + 13B_{2u} + 13B_{3u}$

where all even vibrations are Raman active while odd vibrations are IR active (the center of inversion is present in the crystal).



Fig. 3 Raman scattering spectra of pure and doped forsterite single crystals.

Fig. 3 clearly shows Raman spectrum of forsterite. Some differences can be seen around 300 cm⁻¹ due to doping. These modes can be addressed to cation bonds. Some new modes appeared, while, on the other hand, some were missing. The mode at ~ 588 cm⁻¹ shifted around 10 cm⁻¹ due to dopants (586 cm⁻¹ for pure forsterite, and 582, 584 and 592 cm⁻¹ for NiO₂, V₂O₅, and V₂O₃, respectively). This mode belongs to the SiO₄²⁻ group and it is strongly affected by doping.

Conclusion

IR spectra of pure and doped forsterite single crystals have been studied in the range 50 to 5000 cm⁻¹. We especially paid attention to the influences of cations V^{3+} , V^{5+} , and Ni⁴⁺ on phonon properties of forsterite in the range 365 to 476 cm⁻¹. The mode at 954 cm⁻¹ is split probably due to anharmonicity.

Raman spectra of pure and doped forsterite single crystals showed differences around 300 cm⁻¹. In addition, the mode at ~ 588 cm⁻¹ shifted for 10 cm⁻¹.

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Садржај: Монокристали форстерита су расли из раступа на ваздуху по методи Чохралског. Параметри кристалне решетке су одређивани помоћу методе дифракције Х-зрака праха. Инфрацрвени и Раман спектри чистог и допираног (V^{3+} , V^{5+} , and Ni^{4+}) монокристала Mg_2SiO_4 су измерени на собној температури. Ми смо проучавали фононске особине и дискутовали смо утицај допаната.

Кључне речи: форстерит; дифракција Х-зрака; инфрацрвени спектри; Раман спектри; оптичке особине.